

Ab initio study of GaN properties using VASP software package

Klopov, Mihhail; Kuusk, Ahto; Velmre, Enn; Udal, Andres BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 55-58 : ill

Advances in terahertz technology with emphasis on quantum cascade lasers

Reeder, Reeno; Velmre, Enn; Udal, Andres Elektronika ir elektrotehnika = Electronics and electrical engineering 2010 / p. 47-50 : ill <https://eejournal.ktu.lt/index.php/elt/article/view/9225>

Advantages and limitations of an approach to bioimpedance data acquisition and processing relying on fast low bit rate ADCs

Bilinskis, Ivars; Sudars, K.; Min, Mart; Annus, Paul BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 245-248 : ill

Ambipolar diffusion in a three-carrier semiconductor plasma

Velmre, Enn; Masszi, F. Program of 17th Nordic Semiconductor Meeting, Trondheim, Norway, June 17-20, 1996 1996 / p. 36

Analysis of peak current for current crowding effect in 4H- and 6H-SiC Schottky structures

Kurel, Raido; Rang, Toomas The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 235-236 : ill

Analysis of the basic Schottky parameters for diffusion-welded aluminium contacts to p- and n-type SiC

Korolkov, Oleg; Ljutov, Jevgeni; Kuznetsova, Natalja; Ruut, Jana; Rang, Toomas BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 51-53 : ill

Apparent decrease of diffusion coefficients due to the plasma-induced band gap narrowing

Udal, Andres; Velmre, Enn 19th Nordic Semiconductor Meeting : May 20-23, 2001, Copenhagen, Denmark : abstracts 2001 / p. 22 : ill

Automated XML-based test modelling for mixed-signal circuits

Melik, Andres BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 203-204 : ill

Automatic asphalt pavement crack detection and classification using neural networks

Saar, Tõnis; Talvik, Ott BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 345-348 : ill

Automatic vessel identification system

Haavel, Rein; Tani, Harry BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 181-182 : ill

Baltic Electronics Conference (BEC) series : long and winding road

Rang, Toomas BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 11-16

The basic Schottky parameters for combined diffusion welded and sputter metal contacts

Kuznetsova, Natalja; Korolkov, Oleg; Rang, Toomas; Pikkov, Mihhail BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 47-50 : ill

Basics of electrical measurement : general course

Tamm, Uljas 2003 https://www.ester.ee/record=b1828296*est

BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia

2002 http://www.ester.ee/record=b2150914*est

BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia

2004 http://www.ester.ee/record=b2150914*est

BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference

2006 http://www.ester.ee/record=b2150914*est

BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia

2008 http://www.ester.ee/record=b2150914*est

BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 4-6, 2010, Tallinn, Estonia

2010 http://www.ester.ee/record=b2150914*est

A bio-impedance signal synthesiser (BISS) for testing of an adaptive filtering system

Krivošei, Andrei BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 225-228 : ill

A brief survey of exciton concentration models for Si

Velme, Enn; Udal, Andres The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 19-22 : ill

Charge carrier transport in SiC Schottky interfaces : shape factor approach

Kurel, Raido; Rang, Toomas; Rang, Galina; Kasemaa, Argo BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 87-90 : ill

Chirp-based impedance spectroscopy of piezo-sensors

Saar, Tõnis; Märtnens, Olev; Reidla, Marko; Ronk, Ants BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 339-342 : ill

[Christou, A. Integrating reliability into microelectronics manufacturing. Series on design and measurement in electronic engineering, edited by D.V.Morgan and H.L.Grubin. Wiley, Chichester, 1994. 349 p. : Book review]

Velme, Enn Engineering applications of artificial intelligence 1996 / p. 97 https://www.ester.ee/record=b1200126*est

Clamp mode package diffusion welded power SiC Schottky diodes

Korolkov, Oleg; Kuznetsova, Natalja; Rang, Toomas BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 55-58 : ill

The class of test signals for dynamic testing of AD converters

Land, Raul The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 127-128 : ill

Classical electrodynamics, charge distributions of currents and the metal transistor

Taniloo, Rainer BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 61-64 : ill

CMOS current source for shortened square wave waveforms

Kasemaa, Argo; Annus, Paul BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 119-120 : ill

CMOS SP chip for resistor type semiconductor gas sensors

Kasemaa, Argo; Rang, Toomas The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 255-256 : ill

Compact smart home systems : design and verification of cost effective hardware solutions

Kuusik, Alar 2001 http://www.ester.ee/record=b1622134*est

Comparative characteristics of diffusion welded Al contacts to 6H- and 4H-SiC substrates

Korolkov, Oleg; Rang, Toomas The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 23-26 : ill

Comparison of individual SiC JBS chips and JBS stacks connected in series by diffusion welding

Sleptšuk, Natalja; Korolkov, Oleg; Toompuu, Jana; Rang, Toomas BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 81-84 : ill

Comparison of methods for solving the Schrödinger equation for multiwell heterostructure applications

Udal, Andres; Reeder, Reeno; Velme, Enn; Harrison, Paul Proceedings of the Estonian Academy of Sciences. Engineering = Eesti Teaduste Akadeemia toimetised. Tehnikateadused 2006 / p. 246-261 : ill https://www.ester.ee/record=b1072102*est

Comparison of photon recycling effect in GaAs and GaN structures

Velvre, Enn; Udal, Andres Proceedings of the Estonian Academy of Sciences. Engineering = Eesti Teaduste Akadeemia toimetised. Tehnikateadused 2004 / p. 157-172 : ill https://www.ester.ee/record=b1072102*est

Comparison of Si and SiC devices surge current capability by means of numerical simulations

Velvre, Enn; Udal, Andres BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 77-80: ill

Comparison of uncertainty relations in quantum mechanics and signal processing

Udal, Andres; Kukk, Vello; Velvre, Enn; Klopov, Mihhail 11th International Conference on Squeezed States and Uncertainty Relations and 4th Feynman Festival : June 22-26, 2009, Olomouc, Czech Republic : book of abstracts 2009 / p. 135-136 https://jointlab.upol.cz/icssur2009/doc/bookabs_2nded.pdf

Comparison of uncertainty relations in quantum mechanics and signal processing [Electronic resource]

Udal, Andres; Kukk, Vello; Velvre, Enn; Klopov, Mihhail 11th International Conference on Squeezed States and Uncertainty Relations and 4th Feynman Festival : Olomouc, Czech Republic, June 22-26, 2009 : conference proceedings 2009 / [16] p. [DVD]

Complementary multi guard ring JBS structures : numerical analysis

Koel, Ants; Rang, Toomas; Rang, Galina BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 85-88 : ill

Computer-aided analysis of the GTO thyristor current squeezing effect

Velvre, Enn; Udal, Andres Automation, simulation & measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine = 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 159-171: ill https://www.ester.ee/record=b1064031*est

Control and remote monitoring system of Aids to Navigation

Haavel, Rein; Heinla, Ü.; Käärman, L.; Pikpoom, T.; Rebane, R.; Tani, Harry BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 207-210 : ill

Corrected accounting of electron-hole scattering in cross-term current equations for Si and SiC

Velvre, Enn; Udal, Andres 18th Nordic Semiconductor Meeting, Linköping, June 7-10, 1998 : abstracts 1998 / p. F-88: ill <https://iopscience.iop.org/article/10.1238/Physica.Topical.079a00193>

Corrected accounting of electron-hole scattering in cross-term current equations for Si and SiC

Velvre, Enn; Udal, Andres Physica scripta 1999 / p. 193-197 : ill <https://ui.adsabs.harvard.edu/abs/1999PhST...79..193V/abstract> <http://doi.org/10.1238/Physica.Topical.079a00193>

Critical analysis of uncertainty relations based on signal duration and spectrum width

Udal, Andres; Kukk, Vello; Velvre, Enn Elektronika ir elektrotehnika = Electronics and electrical engineering 2009 / p. 31-34 : ill https://www.ester.ee/record=b1200105*est <https://eejournal.ktu.lt/index.php/elt/article/view/10098>

Department of Electronics

Min, Mart Research activities / Tallinn Technical University 1993 / p. 79-81 https://www.ester.ee/record=b1053754*est

Development of automated measurement setup for standard resistors

Pokatilov, Andrei; Kübarsepp, Toomas BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 161-162

Digitaalelektronika : laboratoorse teo kogumik

1994 http://www.ester.ee/record=b1065462*est

Digitaalelektronika alused : skeemid : abimaterjal loengute jälgimise ja konspekterimise hõlbustamiseks

1994 https://www.ester.ee/record=b1065765*est

DSP-based device for multi-frequency bio-impedance measurement

Märtens, Olev Medical & biological engineering & computing 1999 / Suppl. 1, Proceedings of the 11th Nordic-Baltic Conference on Biomedical Engineering : NBCBME'99 : June 6-10, 1999, Tallinn, Estonia, p. 165-170

A DSP-based laser scanner

Saar, Tõnis; Märtens, Olev BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 345-348 : ill

Eessõna

Meister, Ants; Tamm, Uljas Elektronika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 4 https://www.ester.ee/record=b1399956*est

Efficiency estimation for a broadband 7 THz radiation source with GaAs/AlGaAs parabolic quantum wells

Reeder, Reeno; Ikonic, Zoran; Harrison, Paul; **Udal, Andres**; **Velmre, Enn** The proceedings of the Ninth International Conference on Intersubband Transitions in Quantum Wells : Ambleside, Cumbria, U.K., 9-14th September 2007 2007 / p. P67-2 : ill
https://www.academia.edu/63544688/Efficiency_Estimation_for_a_Broadband_7_THz_Radiation_Source_with_GaAs_AlGaAs_Parabolic_Quantum_Wells

Electrical bioimpedance measurement : methods and equivalent circuits

Gordon, Rauno; **Parve, Toomas** BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 363-366 : ill

Electron microscopy study of contact layers in n-type 4H-SiC after diffusion welding

Korolkov, Oleg; **Sleptšuk, Natalja**; Sitnikova, A.; **Rang, Toomas** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 91-94 : ill

Electronic circuits : examples for project based subject "Technologies of electronic products"

Sillakivi, Peeter; **Tamm, Uljas** 2003 https://www.ester.ee/record=b1828290*est

Electro-thermal simulations and forward surge current failure prediction for SiC diodes

Velmre, Enn; **Udal, Andres** Program of 17th Nordic Semiconductor Meeting, Trondheim, Norway, June 17-20, 1996 1996 / p. 28

Elektrimõõtmiste alused : ülevaatekursus

2003 http://www.ester.ee/record=b1782612*est

Elektrisüsteemi talitluse seire

Meldorf, Mati 1995 http://www.ester.ee/record=b1069180*est

Elektronilülitused : näidisskeemid projektipõhilisele õppeainele "Elektrontoodete tehnoloogiad"

2003 https://www.ester.ee/record=b1828299*est

Elektroonika - mis see on?

Rang, Toomas Elektroonika 2004 : XI rahvusvahelise telekommunikatsioonipäeva materjalid 2004 / lk. 7-9
https://www.ester.ee/record=b1910557*est

Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid

2000 https://www.ester.ee/record=b1399956*est

Elektroonika desintegratsioon

Velmre, Enn Tallinna Tehnikaülikooli aastaraamat 2002 2003 / lk. 33-38 https://www.ester.ee/record=b1212786*est

Elektroonika Eestis - tööstus, teadus, haridus - järelnõtteid

Rang, Toomas Insenerikultuur Eestis. 3 1997 / lk. 139-147 https://www.ester.ee/record=b1063622*est

Elektroonika komponendid : loengukonspekt

Kasemaa, Argo 2003 http://www.ester.ee/record=b1782506*est

Elektroonika kui Eesti innovatsioonisüsteemi infrastruktuur

Min, Mart; **Rang, Toomas**; **Ubar, Raimund-Johannes** Eesti teadlaste kongress, 11.-15. augustini 1996. a. Tallinnas : ettekannete kokkuvõtted 1996 / lk. 265 https://www.ester.ee/record=b1052731*est

Elektroonikainseneride harimisest meil ja mujal

Rang, Toomas Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 7-14
https://www.ester.ee/record=b1399956*est

Elektroonikud ettevõtluses : teadus, arendus, äri

Min, Mart Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 15-18
https://www.ester.ee/record=b1399956*est

11th Baltic Electronics conference BEC2008

Rang, Toomas Estonian journal of engineering 2010 / p. 5-6 : ill

Establishment of national standard of voltage unit in Estonia

Pokatilov, Andrei; Kübarsepp, Toomas BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 157-160

Exercises. Final test questions : supplementary material in the course "Microelectronics"

Rang, Toomas 2003 https://www.ester.ee/record=b1766979*est

The experimental results of reverse recovery effects in power fastrecovery diodes analyzed by numerical model

Velmre, Enn; Udal, Andres; Vaher, G.T.; Tarma, Mati Proceedings International AEGEAN Conference on Electrical Machines and Power Electronics, Kusadasi 27-29 May, 1992 1992 / p. 738-743: fig

Fabrication methods for microfluidic lab-on-chips

Giannitsis, Athanasios; Min, Mart BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 69-72

Failure prediction of power devices under reverse surge current conditions

Freidin, Boris; Velmre, Enn; Udal, Andres ISPSD'92 : Proceedings of the 4th International Symposium on Power Semiconductor Devices & Ics, Waseda University, Tokyo, Japan, 19-21 May 1992 1992 / p. 118-123 : ill <https://doi.org/10.1109/ISPSD.1992.991247>

Foreword

Rang, Toomas; Min, Mart; Ubar, Raimund-Johannes BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 3 https://www.ester.ee/record=b2150914*est

Formal safety validation of mobile robot teleoperation

Vain, Jüri; Suzuki, Satoshi; Kuusik, Alar BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 161-164 : ill

40 years of Electronics Department at Tallinn Technical University

Tamm, Uljas; Velmre, Enn BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 7-10 https://www.ester.ee/record=b2150914*est

Frequency pattern fitting in an extended block-adaptive Fourier analyser - I: indispensable restrictions

Ronk, Ants BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 153-156 : ill

Frequency pattern fitting in an extended block-adaptive Fourier analyser - II: ordering of frequencies and fitting of them on disjoint sets of values

Ronk, Ants BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 217-220

Frequency pattern fitting in an extended block-adaptive Fourier analyser - III: necessary detunings

Ronk, Ants BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 221-224 : ill

Heart bioimpedance 3D FDM modelling with anisotropic tissue properties

Gordon, Rauno BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 175-178 : ill

High performance GaAs power diodes

Voitovitš, Viktor; Rang, Toomas; Rang, Galina; Pikkov, Mihhail BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 111-114 : ill

High phonon-drag thermoelectric efficiency of SiC at low temperatures

Velmre, Enn; Udal, Andres; Grivickas, Vytautas Final program of the 10th International Conference on SiC and Related Materials : ICSCRM'2003 : Lyon, France, Oct. 5-10, 2003 2003 / p. ThP4-13 https://www.researchgate.net/publication/240834700_High_Phonon-Dragefficiency_of_SiC_at_Low_Temperatures

Impact of phonon-drag effect on Seebeck coefficient in SiC : experiment and simulation

Bikbajevs, V.; Grivickas, V.; Stölzer, M.; Velmre, Enn; Udal, Andres; Grivickas, Paulius; Syväjärvi, Mikael; Yakimova, Rositza Abstracts of the Lithuanian National Physics Conference : LNPK-34 : Vilnius, 2003 2003 / p. 219 <http://www.diva-portal.org/smash/record.jsf?pid=diva2%3A269444&dsid=8596>

Improvement of switching lock-in signal conversion in bioimpedance analysers

Parve, Toomas; Land, Raul; Min, Mart; Poola, Gustav BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 179-182 : ill

Influence of excitonic scattering on charge carrier ambipolar diffusion in silicon

Udal, Andres; Velmre, Enn ESSDERC'97 : proceedings of the 27th European Solid-State Device Research Conference, Stuttgart, Germany, 22-24 September 1997 1997 / p. 212-215: ill <https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=1503333>

Intracardiac bio-impedance measurement for cardiac rhythm control

Holmström, Nils; Järverud, Karin; **Min, Mart**; Noren, Kjell; **Parve, Toomas** Medical & biological engineering & computing 1999 / Suppl. 1, Proceedings of the 11th Nordic-Baltic Conference on Biomedical Engineering : NBCBME'99 : June 6-10, 1999, Tallinn, Estonia, p. 163-164: ill

Investigation of charge carrier lifetime temperature-dependence in 4H-SiC diodes

Velmre, Enn; **Udal, Andres** Silicon carbide and related materials 2006 2007 / p. 375-378

https://www.researchgate.net/publication/250348987_Investigation_of_Charge_Carrier_Lifetime_Temperature-Dependence_in_4H-SiC_Diodes

Investigation of p-i-n GaAs structures by DLTS method

Toompuu, Jana; **Korolkov, Oleg**; **Sleptšuk, Natalja**; **Rang, Toomas** Elektronika ir elektrotehnika = Electronics and electrical engineering 2010 / 4, p. 51-54 : ill

https://www.researchgate.net/publication/267372152_Investigation_of_p-i-n_GaAs_structures_by_DLTS_method

Jaapani professor esines Tallinna Tehnikaülikoolis : [Tohoku Ülikooli prorektor ja biomeditsiinielektronika labori juhataja Nozomu Hoshimiya]

Min, Mart; **Velmre, Enn** Mente et Manu 2001 / lk. 3 : portr https://www.ester.ee/record=b1242496*est

Kalman Tarnay (1929 - 1998)

Rang, Toomas The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. V : portr

Kui vana on elektroonika?

Velmre, Enn Elektroonika 2004 : XI rahvusvahelise telekommunikatsioonipäeva materjalid 2004 / lk. 53-56

https://www.ester.ee/record=b1910557*est

Kui vana on elektroonika? : ettekanne rahvusvahelise telekommunikatsioonipäeva konverentsil "Elektroonika 2004" 14. mail 2004 TTÜs

Velmre, Enn Tallinna Tehnikaülikooli aastaraamat 2004 2005 / lk. 291-296 : ill https://www.ester.ee/record=b1212786*est

Kunstnina

Kasemaa, Argo Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 95-102 : ill https://www.ester.ee/record=b1399956*est

Laterally pumped GaAs/AlGaAs quantum wells as sources of broadband terahertz radiation

Reeder, Reeno; Ikonic, Zoran; Harrison, Paul; **Udal, Andres**; **Velmre, Enn** Journal of applied physics 2007 / [6] p. : ill

<https://pubs.aip.org/aip/jap/article/102/7/073715/987937/Laterally-pumped-GaAs-AlGaAs-quantum-wells-as> <https://doi.org/10.1063/1.2783779>

Low power CMOS current source for shortened square wave signals

Kasemaa, Argo; **Rang, Toomas** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 89-92 : ill

Low power SC structures with low threshold MOS switches

Männamaa, Vello; **Sabolotny, Rein** The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 75-78 : ill

Low quiescent current LDO with improved load transient

Strik, Sergei; Strik, Viktor BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 127-130

LPE structures for power GaAs rectifiers

Voitovitš, Viktor The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 237-240 : ill

https://artiklid.elnet.ee/record=b1005558*est

LPE technology for power GaAs diode structures

Voitovitš, Viktor; **Rang, Toomas**; **Rang, Galina** Estonian journal of engineering 2010 / p. 11-22 : ill

Measurement of charge carrier lifetime temperature dependence in 4H-SiC power diodes

Velmre, Enn; **Udal, Andres** Abstracts of International Conference on Silicon Carbide and Related Materials : ICSCRM'99 : October 10-15, 1999, Research Triangle Park, North-Carolina, USA 1999 / paper no 394, 2 p

https://www.researchgate.net/publication/240833834_Measurement_of_Charge_Carrier_Lifetime_Temperature-Dependence_in_4H-SiC_Power_Diodes

Measurement of charge carrier lifetime temperature-dependence in 4H-SiC power diodes

Udal, Andres; **Velmre, Enn** Proceedings of the International Conference on Silicon Carbide and Related Materials - 1999

(ICSCRM'99) : Research Triangle Park, North-Carolina, USA, Oct. 10-15, 1999. Vol. 1 2000 / p. 781-784
<https://www.scientific.net/MSF.338-342.781>

Medical and context data acquisition system for patient home monitoring

Reilent, Enar; Lõõbas, Ivor; **Pahtma, Raido; Kuusik, Alar** BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 269-272

Modeling and simulation of bipolar semiconductor devices : authors's main publications

Velmre, Enn 1996 http://www.ester.ee/record=b2079366*est

Modeling in semiconductor electronics

Javor, A.; **Rang, Toomas**; Szekeley, V.; Tarnay, K.; **Velmre, Enn** 1993 https://www.ester.ee/record=b1031052*est

Modeling in the bioimpedance measurement techniques using general-purpose software

Paavle, Toivo BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 209-212 : ill

Modeling of a carbon nanotube junction with ab-initio software VASP

Velmre, Enn; Klopov, Mihhail; Udal, Andres BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 75-78 : ill

Modeling of charge carrier non-isothermal transport parameters in silicon

Velmre, Enn; Udal, Andres BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 71-74: ill

Modeling of lattice heat conductivity and thermopower in SiC considering the four-phonon scattering processes

Velmre, Enn; Udal, Andres Material science forum 2003 / p. 391-394 <https://www.scientific.net/MSF.433-436.391>

Modeling of photon recycling in GaN-devices

Velmre, Enn; Udal, Andres; Klopov, Mihhail 5th European Conference on Silicon Carbide and Related Materials : book of abstracts : 31 August-4 September 2004, Bologna, Italy 2004 / p. 317-318
https://www.researchgate.net/publication/250344144_Modeling_of_Photon_Recycling_in_GaN-Devices

Modeling of the PLL-based bioimpedance measurement system

Paavle, Toivo; Min, Mart BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 183-186 : ill

Modelling of charge carrier non-isothermal transport in silicon and silicon carbide

Velmre, Enn; Udal, Andres Proceedings of the Estonian Academy of Sciences. Engineering 2000 / p. 144-154 : ill
https://artiklid.elnet.ee/record=b1004044*est

Modelling of Seebeck coefficient influenced by carrier phonon drag and mixed scattering

Milatškov, Milko BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 57-60 : ill

Modelling of the tunneling current in metal alloy contacts to 6H- and 4H-SiC substrates

Rang, Toomas MICROSIM II : simulation and design of microsystems and microstructures 1997 / p. 23-31 : ill

A modified frequency error estimator for the block adaptive Fourier analyzer

Ronk, Ants The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 103-106 : ill https://www.ester.ee/record=b2150914*est

Multisine dynamic EBI spectrum analyser for in vivo experiments

Min, Mart; Märtnens, Olev; Parve, Toomas Medical & biological engineering & computing 1999 / Suppl. 2, Proceedings of the European Medical & Biomedical Engineering Conference : EMBE'99 : November 4-7, 1999, Vienna, Austria. Part 1, p. 144-145

Nanotehnoloogiad : sõnastik. Osa 1, Tuumik-sõnavara = Nanotechnologies : vocabulary. Part 1, Core terms

2011 https://www.ester.ee/record=b2707940*est

Nanotehnoloogiad : sõnastik. Osa 3, Süsinik-nanoobjektid = Nanotechnologies : vocabulary. Part 3, Carbon nano-objects

2011 https://www.ester.ee/record=b2707947*est

Nanotehnoloogiat meilt ja mujalt

Velmre, Enn Elektriala 2005 / lk. 22-24 : ill

Negative resistance structures : optimization of power balance

Taniloo, Rainer The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 353-354 : ill

Neli teadusdoktorit lisaks : [Heinrich Rešetnjak, Jüri Pirso, Paul Kallas, Enn Velmre]

Kulu, Priit; Männama, Vello Tehnikaülikool 1996 / lk. 3: ill https://www.ester.ee/record=b5309277*est

New interdisciplinary master program in communicative electronics at Tallinn University of Technology

Rang, Toomas; Sleptšuk, Natalja 5th International Conference on Interdisciplinarity in Education ICIE'10 : New Higher Education Programs, June 17-19, 2010, Tallinn, Estonia : proceedings 2010 / p. 187-190 : ill

Numerical investigation of digitised parabolic quantum wells for terahertz AlGaAs/GaAs structures

Reeder, Reeno; Udal, Andres; Velmre, Enn; Harrison, Paul BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 51-54 : ill

Numerical simulation of electrothermal effects in ESD protection devices

Hellström, Sven; **Freidin, Boris; Velmre, Enn; Udal, Andres** ESREF'92: 3rd European Symposium on Reliability of Electron Devices, Failure Physics and Analysis : 5-8 October 1992, Schwäbisch Gmünd, Germany : conference proceedings 1992 / p. 77-80 <https://d-nb.info/921228503/04>

Numerical simulation of electrothermal interactions in semiconductor devices experiencing ESD pulses

Freidin, Boris; Velmre, Enn; Udal, Andres Techn. Dig. of International Workshop on Computational Electronics, 1992 May 28-29, Beckman Institute, Univ. of Illinois Urbana-Champaign, USA 1992 / p. 75-78 : ill https://in4.iue.tuwien.ac.at/pdfs/iwce/iwce1_1992/pdfs/pp075-078.pdf

Numerical study of turn-off phenomenon in complementary 4H-SiC JBS rectifiers

Rang, Toomas; Kurel, Raido; Higelin, G. BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 47-50 : ill

Näidisülesanded. Test : abimaterjal ainele "Mikroelektronika"

2003 http://www.ester.ee/record=b1766976*est

One bio-medical multisine measurement task: solution principles

Ronk, Ants; Min, Mart BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 199-200 : ill

Optimization of electrowetting electrodes : analysis of the leakage current characteristics of various dielectric layers

Cahill, Brian; Giannitsis, Athanasios; Land, Raul; Min, Mart BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 79-82 : ill

Phase and frequency stability of PLL systems

Land, Raul Automation, simulation & measurement. Section A, Automation. Section M, Measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991 = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 100-107: ill

Phase insensitivity in the charge pump phase locked loops

Paavle, Toivo Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / p. 78-86 : ill https://www.ester.ee/record=b1399956*est

Phase-domain modeling of the PLL frequency synthesizers

Paavle, Toivo BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 173-176 : ill

Phase-frequency detector modeling for the PLL applications

Männama, Vello; Paavle, Toivo The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 119-122 : ill

Plaan 3000Pluss

Rang, Toomas *Mente et Manu* 2010 / lk. 3 : fot https://artiklid.elnet.ee/record=b2286893*est

Pooljuhtkomponentide simuleerimine arvutil : laboratoorse töö juhend

2003 http://www.ester.ee/record=b1766958*est

Precision AC/DC measurement converters with switched capacitors in the feedback path = Täpsed vahelduvpinge mõõtemuundurid ümberlülituvate kondensaatoritega tagasiside ahelas

Märtens, Olev 1993 http://www.ester.ee/record=b2089954*est

Preface

Rang, Toomas BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 3-4
https://www.ester.ee/record=b2150914*est

Preface

Rang, Toomas BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. III https://www.ester.ee/record=b2150914*est

Preface

Rang, Toomas The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. III https://www.ester.ee/record=b2150914*est

Preface

Rang, Toomas BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. III https://www.ester.ee/record=b2150914*est

Preface

Rang, Toomas BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 3-4 https://www.ester.ee/record=b2150914*est

Preface

Rang, Toomas BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 3-4 : fot
http://www.ester.ee/record=b2150914*est

Preface

Rang, Toomas BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 3-4 : fot
http://www.ester.ee/record=b2150914*est

Preliminary approach to the timing measurements for reverse recovery applied to the SiC Schottky diode model

Pikkov, Mihhail The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 321-322 : ill

Preliminary investigation of diffusion welded contacts to p-type 6H-SiC

Korolkov, Oleg; Rang, Toomas; Kuznetsova, Natalja; Ruut, Jana BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 55-56 : ill

Principles of semiconductor structures. Realisation of structures in crystals : supplementary lecture material in the subject "Microelectronics"

Rang, Toomas 2003 http://www.ester.ee/record=b1782565*est

Process instrumentation for impedance spectroscopy - a modular concept

Nacke, T.; **Land, Raul;** Barthel, A. BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 235-238 : ill

Product and manufacturing in electronics : supplementary material in the subject "Technologies of electronic circuits"

Rang, Toomas 2003 https://www.ester.ee/record=b1766953*est

Pseudorandom sampling in a multi-frequency bioimpedance analyser

Märtens, Olev; Min, Mart BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 253-256 : ill

Quantum mechanical transforms between x- and k-space as a signal processing problem

Udal, Andres; Kukk, Vello; Velmre, Enn; Klopov, Mihhail BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 71-74 : ill https://www.ester.ee/record=b2150914*est

The realization of the precision system for phase and harmonics measurement

Eek, Andres; Kolk, Arno Automation, simulation & measurement. Section A, Automation. Section M, Measurement : 3rd biennial

conference : Tallinn, Estonia, October 7-11, 1991 = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 95-99: ill https://www.ester.ee/record=b1064034*est

Reconfigurable data acquisition unit for bioimpedance measurements

Pesonen, Vadim; Gorev, Maksim; Annus, Paul; Min, Mart; Ellervee, Peeter BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 257-260 : ill

SC structures with low-threshold MOS switches

Männama, Vello; Sabolotny, Rein BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 119-122 : ill

A set-up for investigation of post-ischaeamic recovery of isolated animal heart based on dynamic measurement of pressure, flow, and electrical bioimpedance

Rätsep, Indrek; Kink, Andres; Taal, Günter; Parve, Toomas BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 367-370 : ill

Short-time chirp excitations for using in wideband characterization of objects: an overview

Paavle, Toivo; Min, Mart; Ojarand, Jaan; Parve, Toomas BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 253-256 : ill

SiC Schottky diode for use in power convertors

Pikkov, Mihhail; Rang, Toomas; Pokatilov, Andrei BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 245-246 : ill

SiC-diodes forward surge current failure mechanisms : experiment and simulation

Velvre, Enn; Udal, Andres ESREF'97 : proceedings of the 8th European Symposium on Reliability of Electron Devices, Failure Physics and Analysis, Oct. 7-10, 1997, Bordeaux, France 1997 / p. 1671-1674
<https://www.sciencedirect.com/science/article/abs/pii/S0026271497001364>

SiC-diodes forward surge current failure mechanisms : experiment and simulation

Udal, Andres; Velvre, Enn Microelectronics reliability 1997 / p. 1671-1674 [https://doi.org/10.1016/S0026-2714\(97\)00136-4](https://doi.org/10.1016/S0026-2714(97)00136-4)

Simple DSP interface for impedance spectroscopy of piezo-sensors

Märtens, Olev; Reidla, Marko; Saar, Tõnis BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 343-344 : ill

Simplified DFT with sorted accumulation of input samples

Märtens, Olev BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 329-332 : ill

Simulation of intra-cardiac complex impedance signals for developing simple bio-impedance models for cardio-dynamics

Gordon, Rauno BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 213-216 : ill

Simulation of semiconductor components on PC-s : instruction for laboratory work

Kurel, Raido 2003 http://www.ester.ee/record=b1766967*est

Smart house

Kuusik, Alar Integrated systems and design : interstudy, May 9, 2008 2008 / p. 65-72

Smart sensing and Time of Arrival based location detection in Parking Management Services

Männi, Urmo BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 213-214 : ill

SoC based mobile robot telecontrol system

Kuusik, Alar BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 153-154 : ill

Software architecture for swarm mobile robots

Vain, Jüri; Tammet, Tanel; Kuusik, Alar; Reilent, Enar BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 231-234 : ill

Static and dynamic behavior of the SiC complementary JBS structures

Kurel, Raido; Rang, Toomas BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference 2006 / p. 59-62 : ill

The structure of FET-based negative differential resistance for microwave and neural network applications

Taniilo, Rainer BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 73-76 : ill

Study of radiative recombination influence in GaN and GaAs bipolar transistor structures

Velme, Enn; Udal, Andres; Verbitski, Irina BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 59-62 : ill

Synchronous primary signal processing for MIMO bio-impedance measurement on several frequencies

Ronk, Ants; Toomessoo, Jüri BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 313-316 : ill

Tallinna Tehnikaülikool ja Elcoteq Tallinn AS elektroonikainseneride ettevalmistuse ühisrindel

Rang, Toomas Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 19-20 https://www.ester.ee/record=b1399956*est

Termoelektri avastaja Thomas Johann Seebeck : [ettekanne rahvusvahelisel seminaril 11. mail 2007 TTÜs]

Velme, Enn Tallinna Tehnikaülikooli aastaraamat 2007 2008 / lk. 335-339

Test development and deployment tool-set for mixed-signal and digital devices

Mellik, Andres; Raik, Jaan BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 163-166 : ill

The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings

2000 https://www.ester.ee/record=b2150914*est

A theoretical study of electron drift mobility anisotropy in n-type 4H- and 6H-SiC

Velme, Enn; Udal, Andres Abstracts of International Conference on Silicon Carbide and Related Materials : ICSCRM'99 : October 10-15, 1999, Research Triangle Park, North-Carolina, USA 1999 / paper no 395, 2 p
https://www.researchgate.net/publication/250338907_A_Theoretical_Study_of_Electron_Drift_Mobility_Anisotropy_in_n-Type_4H-and_6H-SiC

A theoretical study of electron drift mobility anisotropy in n-type 4H- and 6H-SiC

Velme, Enn; Udal, Andres Materials science forum 2000 / p. 725-728

Thermopower measurements in 4H-SiC and theoretical calculations considering the phonon drag effect

Grivickas, Vytautas; Stölzer, M.; **Velme, Enn; Udal, Andres;** Grivickas, Paulius; Syväjärvi, Mikael; Yakimova, Rositza; Bikbajevs, V. Silicon Carbide and Related Materials : ECSCRM2000 : proceedings of the 3rd European Conference on Silicon Carbide and Related Materials : Kloster Banz, Germany, September 2000 2001 / p. 491-494 : ill
https://www.researchgate.net/publication/240833914_Thermopower_Measurements_in_4H-SiC_and_Theoretical_Calculations_Considering_the_Phonon_Drag_Effect

Thermopower measurements in 4H-SiC and Theoretical calculations considering the phonon drag effect

Grivickas, V.; Stölzer, M.; **Velme, Enn; Udal, Andres;** Grivickas, P.; Syväjärvi, M.; Yakimova, R.; Bikbajevs, V. Abstracts of the 3rd European Conference on Silicon Carbide and Related Materials : ECSCRM'2000 : Sept. 3-7, 2000, Kloster Banz, Germany 2000 / p. 144

Thomas Johann Seebeck (1770-1831)

2007 http://www.ester.ee/record=b2285820*est

Thomas Johann Seebeck and his contribution to the modern science and technology

Velme, Enn BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 17-24 : ill

Time optimal design of the precision third order tracking systems

Min, Mart Automation, simulation & measurement. Section A, Automation. Section M, Measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991 = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 128-134: ill https://www.ester.ee/record=b1064034*est

Toode ja tootmine elektroonikas : abimaterjal ainele "Elektroonikaskeemide tehnoloogiad"

2003 http://www.ester.ee/record=b1766950*est

Towards scalable proofs of robot swarm dependability

Vain, Jüri; Tammet, Tanel; Kuusik, Alar; Juurik, Silver BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 199-202 : ill

Two-dimensional nonisothermal analysis of the current crowding effect at nonuniform SiC Schottky contacts using device simulator DYNAMIT-2DT

Kurel, Raido; Udal, Andres BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 51-54 : ill

Two-dimensional surge current modeling of packaged power devices

Udal, Andres; Freidin, Boris; Velmre, Enn The Bug Exterminator : a monthly publication of Silvaco International 1992 / p. 6-7

Täpsete järgivsüsteemide dünaamika uurimine : magistritöö

Tammemägi, Jaak 1995 https://www.ester.ee/record=b2078796*est

Usage of microfluidic lab-on-chips in biomedicine

Giannitsis, Athanasios; Min, Mart BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 249-252

Using of chirp excitation for bioimpedance estimation : theoretical aspects and modeling

Paavle, Toivo; Min, Mart; Parve, Toomas BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 325-328 : ill

Voolu tekitava laengujaotuse probleem elektrijuhis ja võimendava laengutüürimise väljavaated selles

Taniilo, Rainer Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 71-77 https://www.ester.ee/record=b1399956*est

Überblick der Situation in der Deutschen Elektronik- und Informatikindustrie

Rang, Toomas Automation, simulation & measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / S. 11-25: ill https://www.ester.ee/record=b1064031*est

Ühtne meresidesüsteem

Märtin, Hannes Elektroonika 2000 : VII rahvusvahelise telekommunikatsioonipäeva konverentsi ettekannete materjalid 2000 / lk. 68-70 : ill https://www.ester.ee/record=b1399956*est

Влияние распределения времени жизни электронов и дырок на процесс обратного восстановления р+-n-n+-диодов

Velmre, Enn; Dermenži, Pantelei; Udal, Andres Электротехника : научно-технический журнал 1984 / с. 47-51 https://www.ester.ee/record=b2164206*est

Обобщенные формулы для анализа лавинного умножения носителей заряда в рn-переходах

Velmre, Enn Automation, simulation & measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / с. 172-183: ил https://www.ester.ee/record=b1064031*est

Расчет и оптимизация параметров запираемых тиристоров с учетом внешней цепи

Куузик Э.И.; Кыверик К.Х.; Свирин А.В.; **Udal, Andres** Automation, simulation & measurement : 3rd biennial conference : Tallinn, Estonia, October 7-11, 1991. Section S, Simulation = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / с. 184-199: ил https://www.ester.ee/record=b1064031*est